

Characteristics of SiPM at various Temperature

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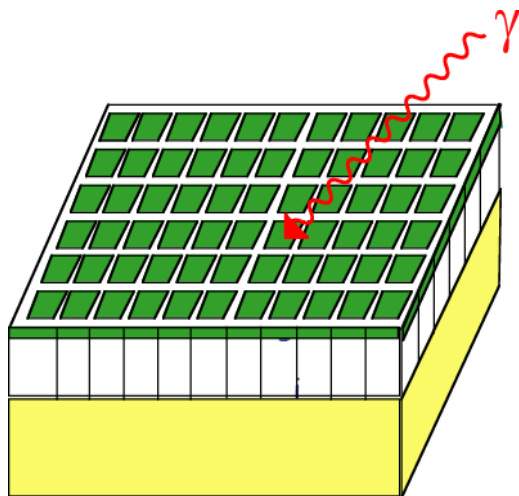
TIFR, Mumbai, India

- **Introduction to SiPM signal and noise**
- **Fit to extract slope**
- **Recovery time**
- **Fraction of prompt Cross talk events**
- **Ratio of After Pulse + Delayed Cross talk**
- **Conclusion**

These results are based on only noise signal of SiPM, though similar study were done with LED source also.

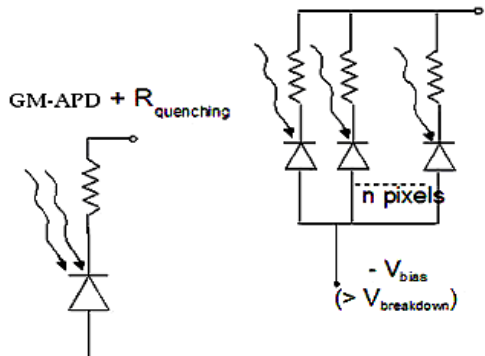
Disclaimer : No systematic uncertainty on the results, only statistical error from number counting and/or fit.

Signal shape and noises in SiPM

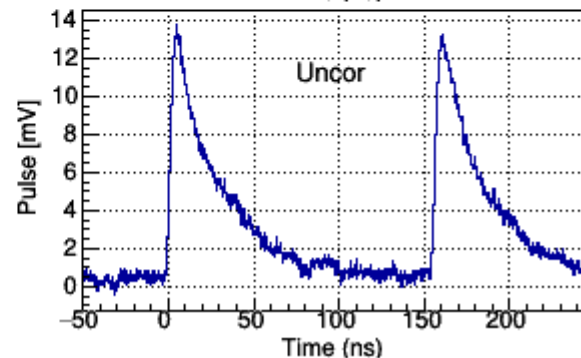
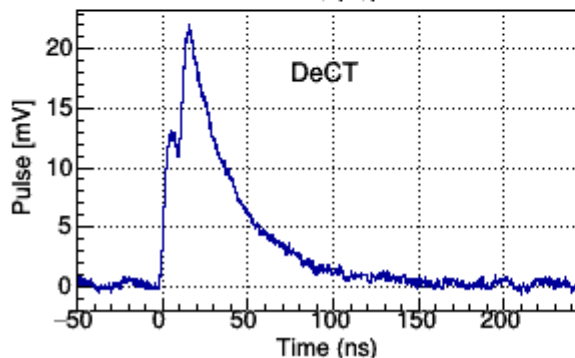
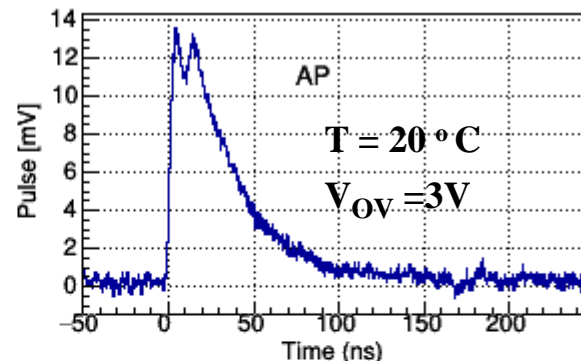
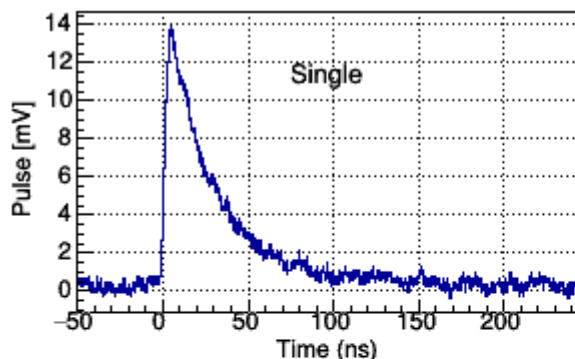
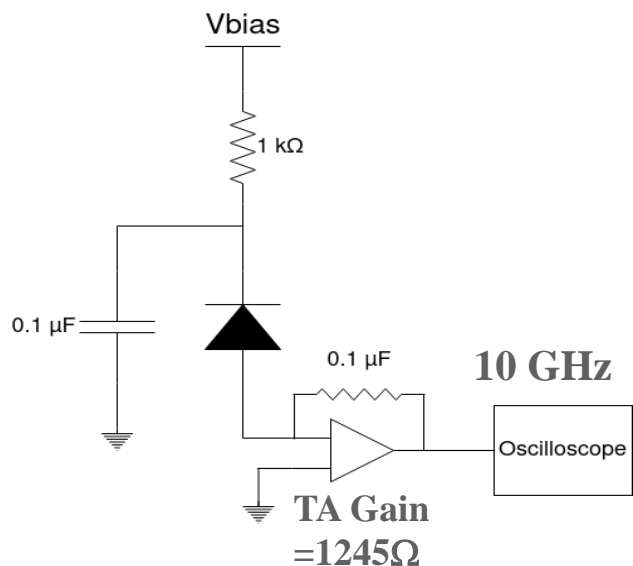


SiPM:

- matrix of n pixels (~ 1000) in parallel
- each pixel: GM-APD + $R_{\text{quenching}}$



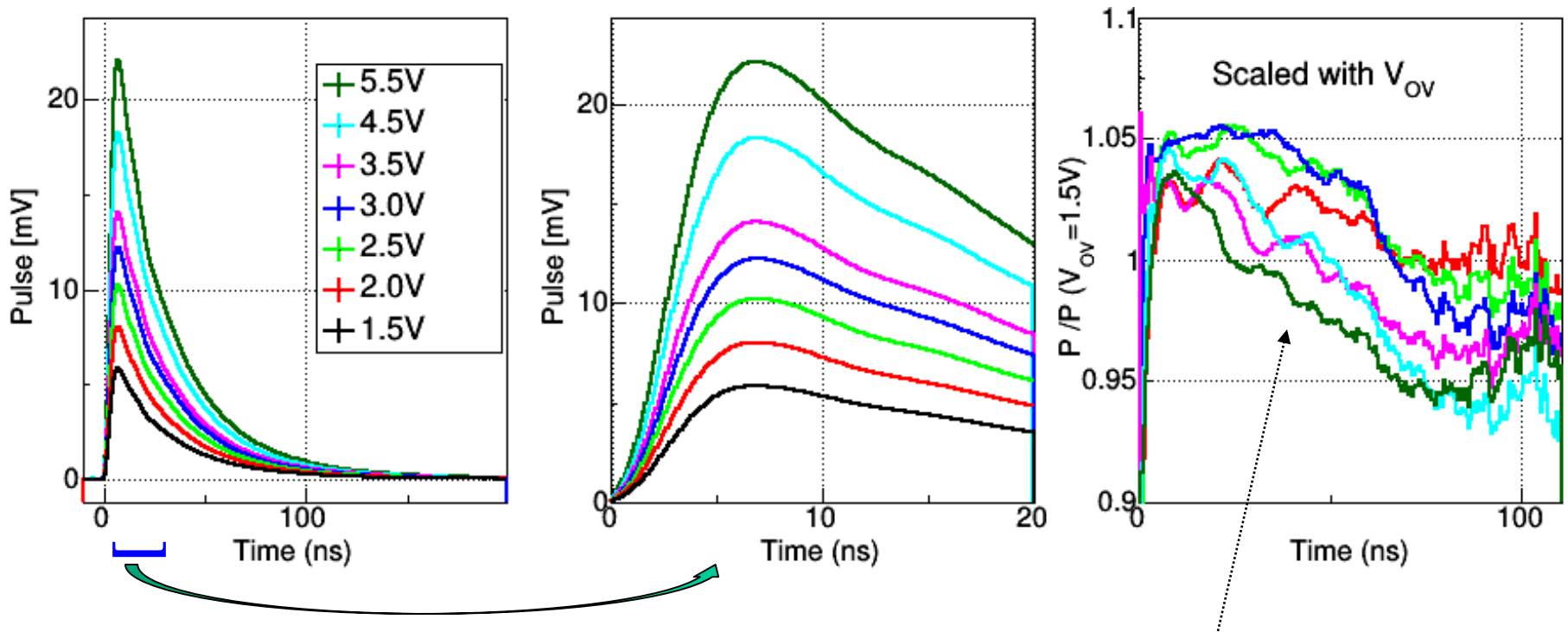
- The SiPM under test is from Hamamatsu (S13360-2050VE) with photosensitive area of $2 \text{ mm} \times 2 \text{ mm}$ and a pixel pitch of $50 \mu\text{m}$,
- breakdown voltage of $(53 \pm 5) \text{ V}$,
- $dG/dV \sim 0.7 \times 10^6$
- $dV_{\text{th}}/dT \sim 55 \text{ mV}/^\circ\text{C}$ and
- $-dG/dT = 2\%$



Signal shapes at various overvoltage @T=20°C

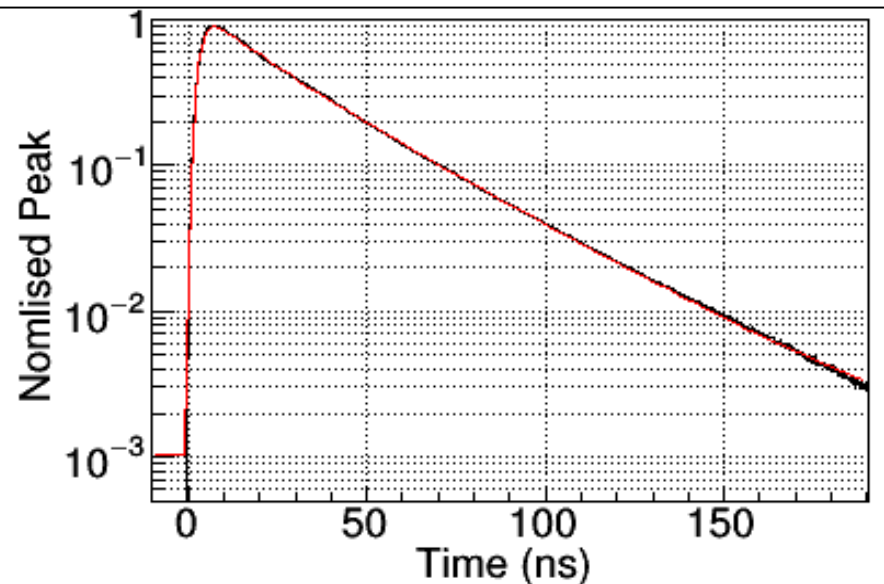
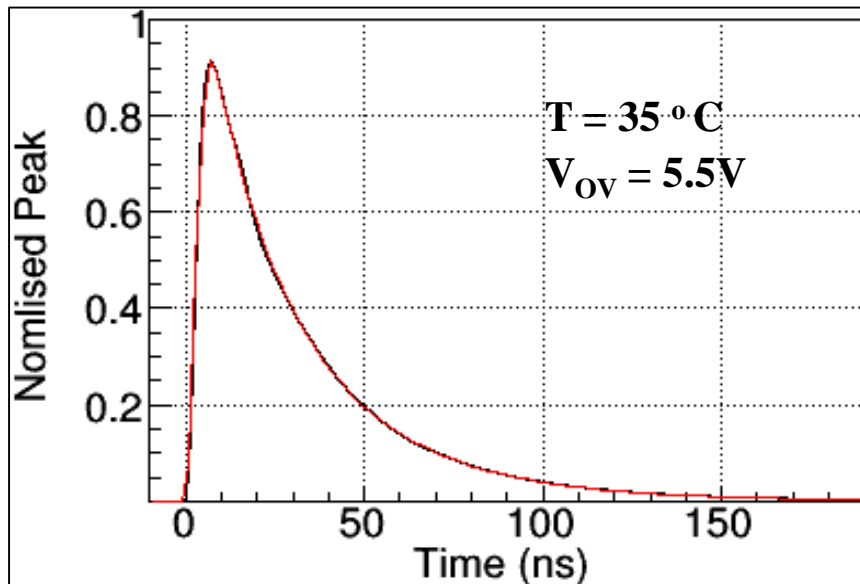
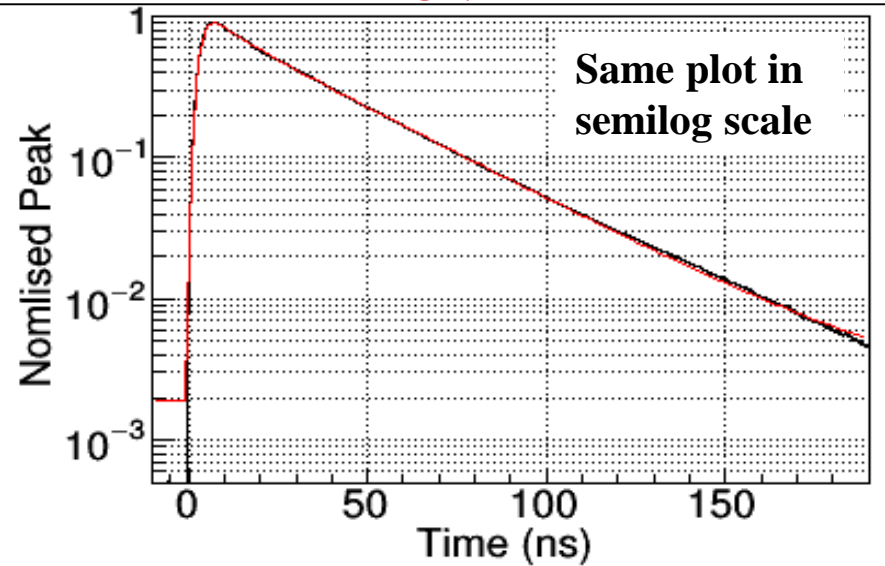
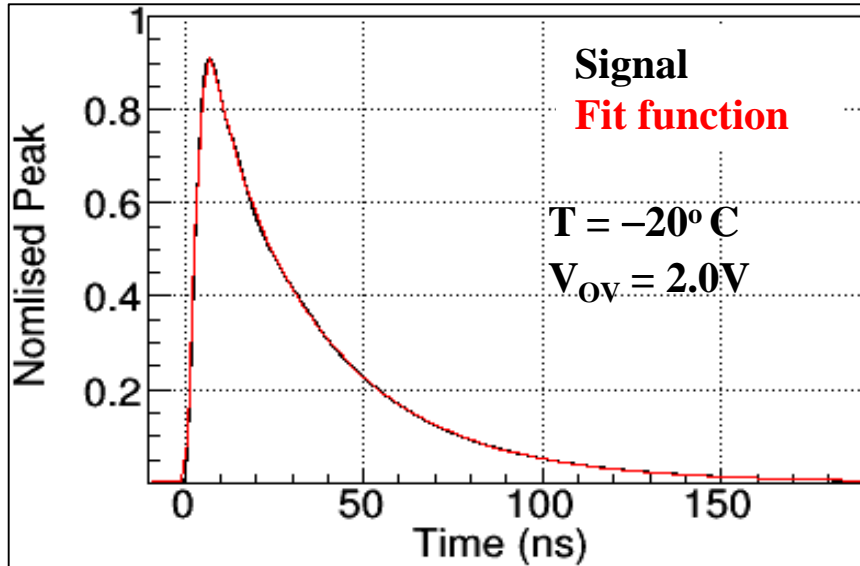
- It is well known that the recovery time depends on the temperature
 - Is there any variation due to V_{OV} ?

Superimpose many data by adjusting the starting time, use χ^2 criteria to remove events with correlated noises → Reduce the fluctuation of individual signal



- Normalised wrt to V_{OV} and take ratio with respect to data at $V_{OV} = 1.5V$
- There are fluctuations, possible noise in electronics,....
 - But a clear trend that the shape (both raising and falling parts) depends on V_{OV}

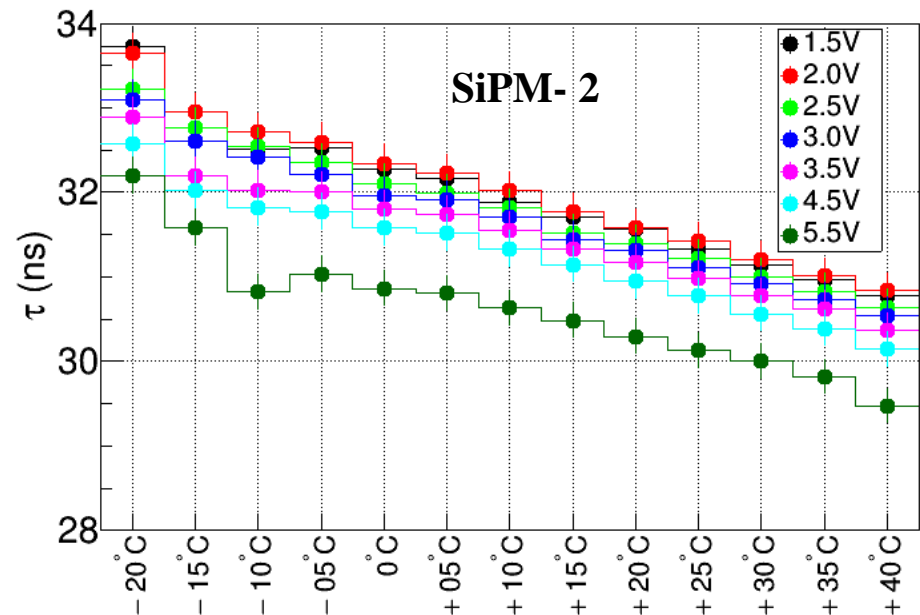
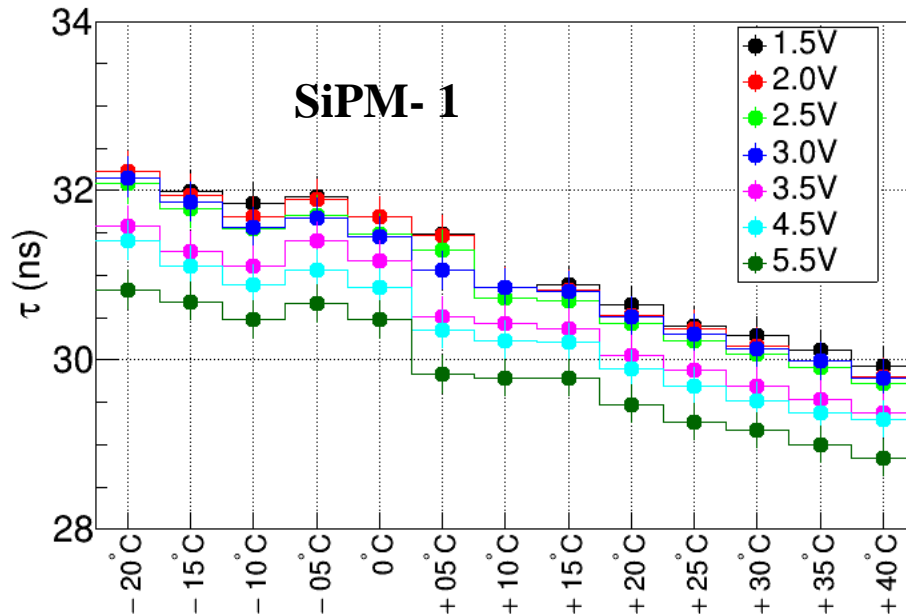
Signals at different V_{OV}



Signal are fitted with a function which includes growth of signal and two exponential falling curves.

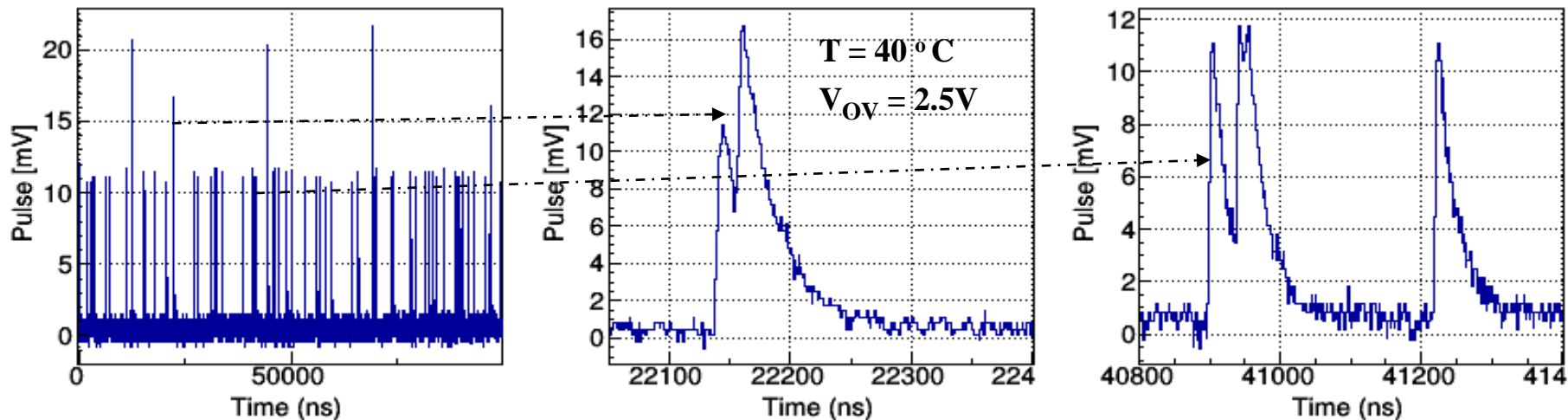
Variation of falling components with V_{OV}

- Fit the signal shape, where the area and relative slope of the second component are fixed
- Similarly, parameters of rising components.
- There are correlations among all these

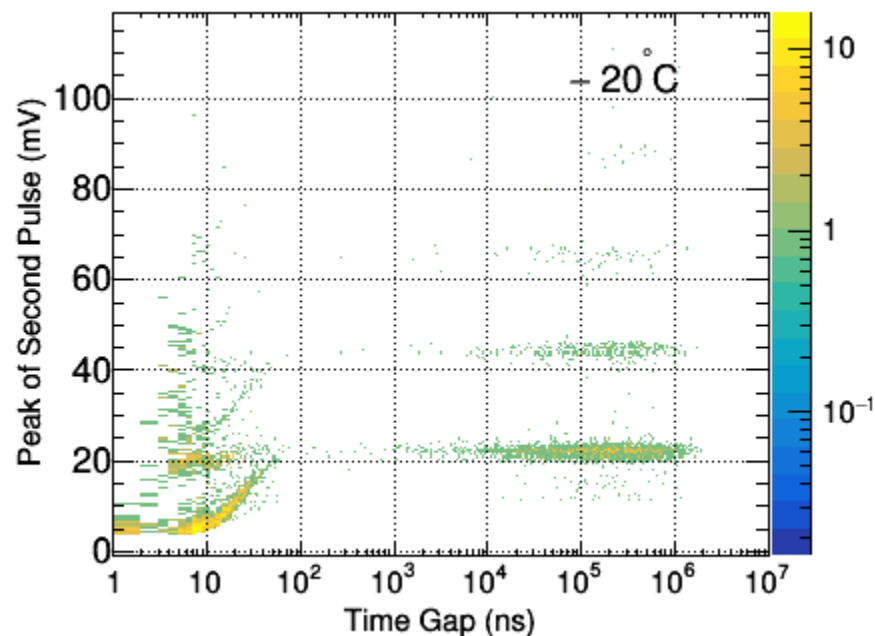
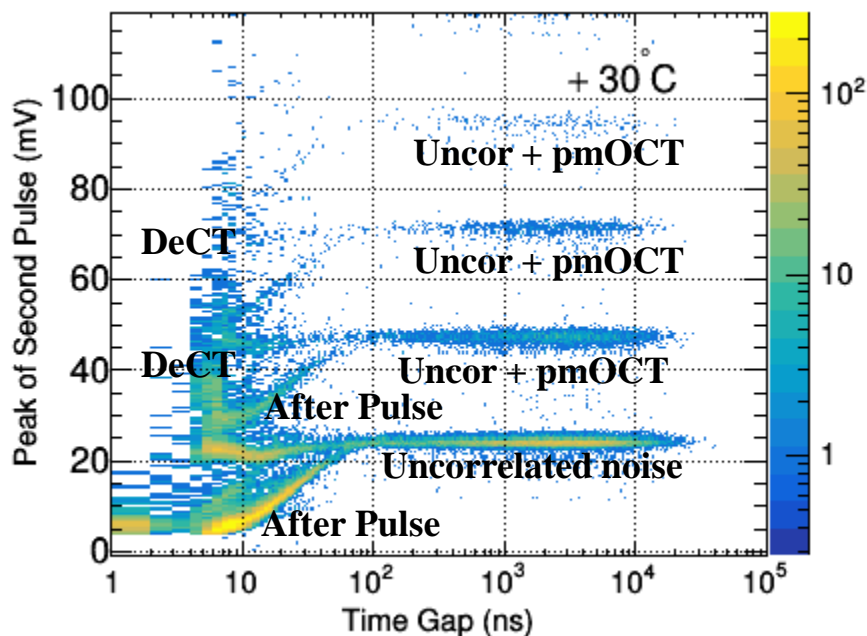


- Variation of τ with temperature is well known
- But also observe a variation with V_{OV}
 - A possible explanation is that the removal of large number of hole for high gain takes longer time

Signal of SiPM with a large time scale

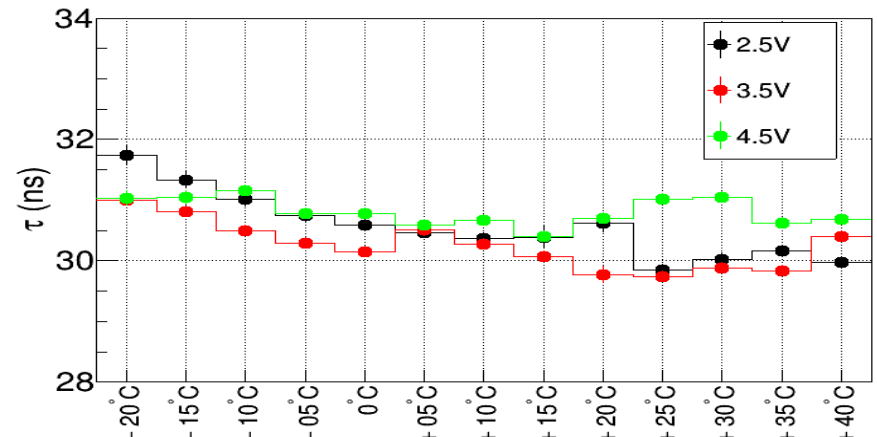
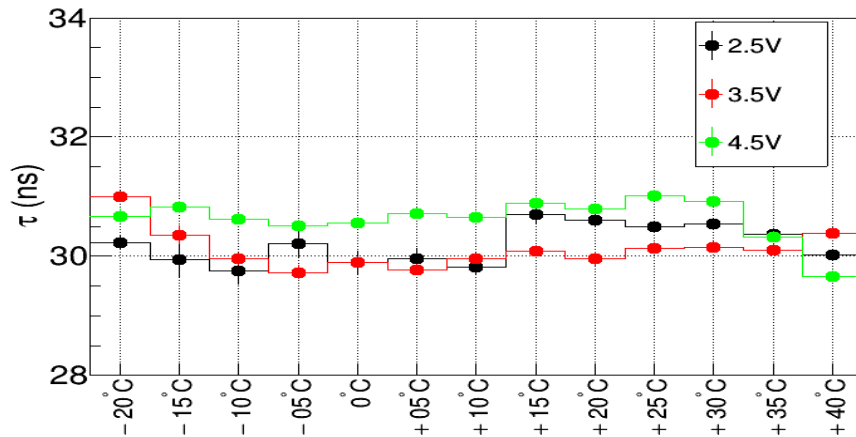
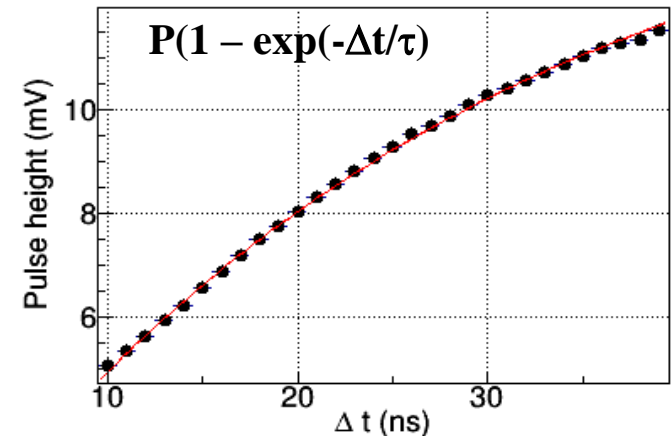
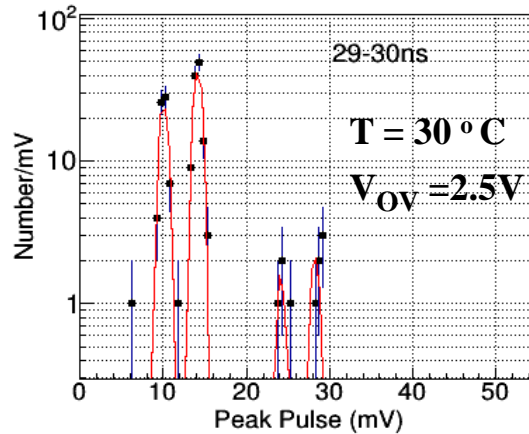
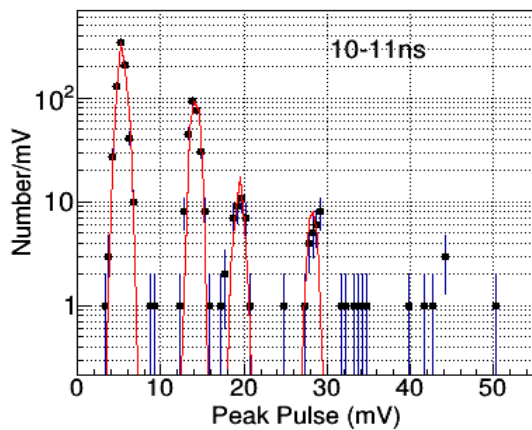
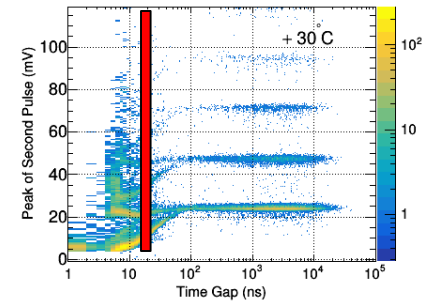


- Find out all these peaks and get a correlation of the pulse height of second peak and time gap



Recovery time

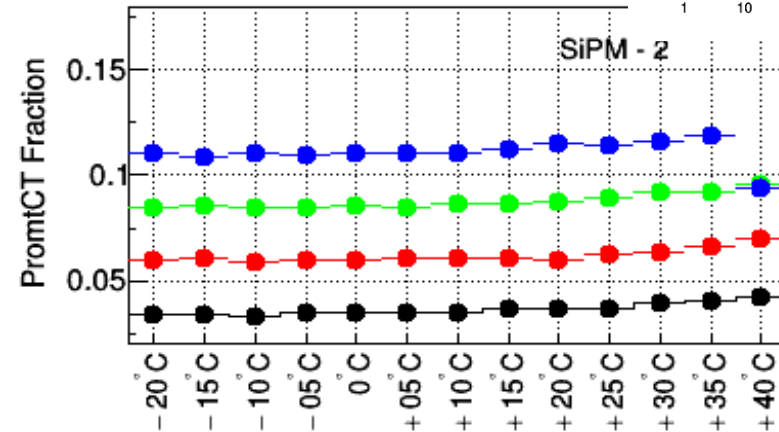
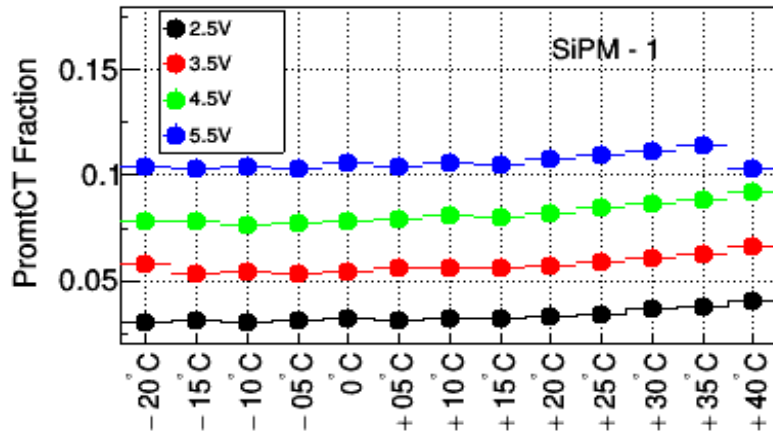
- Fitted signals in Δt time window with four Gaussian functions to find the peaks of AP signals
- Fit the peak position vs Δt to get recovery time



- Range of Δt is very small as well as number of event to have accurate numbers, but
 - There is no clear trends of variation in Recovery time with temperature, V_{OV}
 - Need more data and better algorithm to have data with larger range of Δt

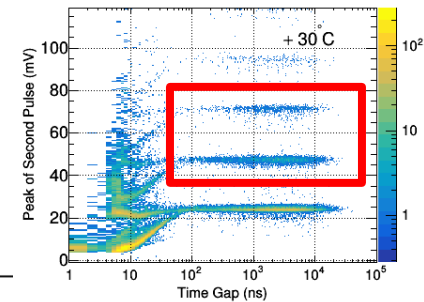
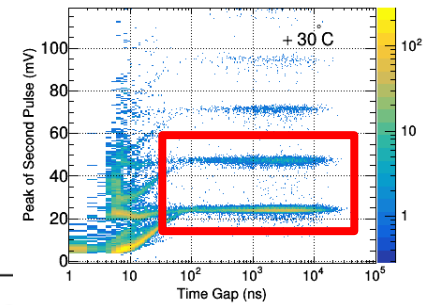
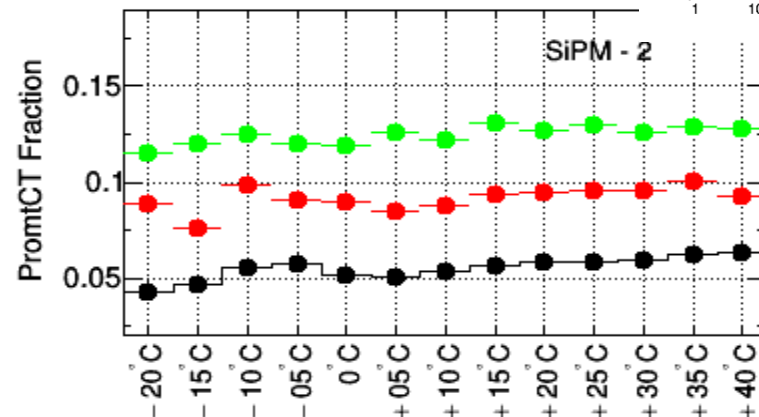
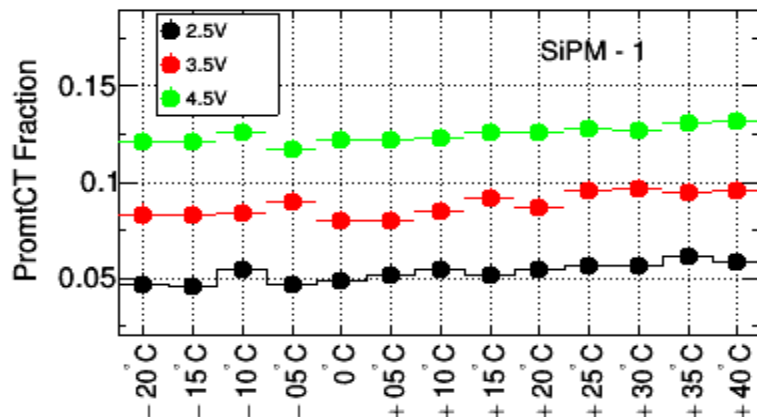
Prompt cross-talk

- Ratio of 2nd and 1st band
 - Expect to have dependency on the gain/ V_{OV} of SiPM

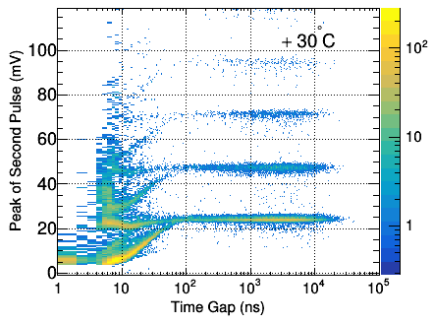


Also a small variation with temperature,

- Ratio of 3rd and 2nd band
 - Expect to have large ratio wrt 2nd/1st band



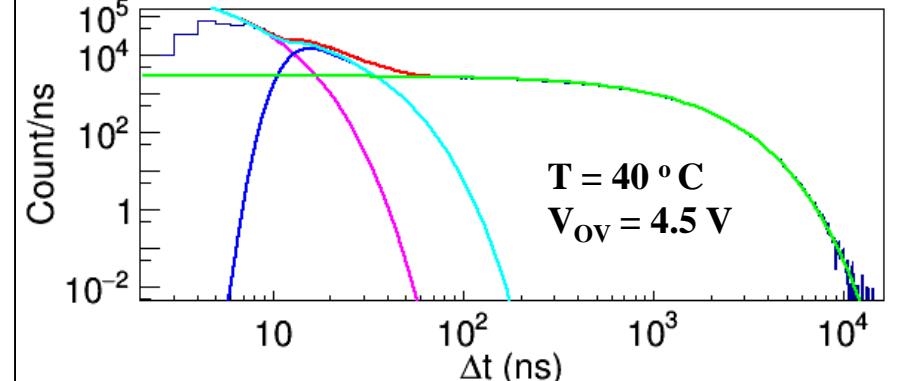
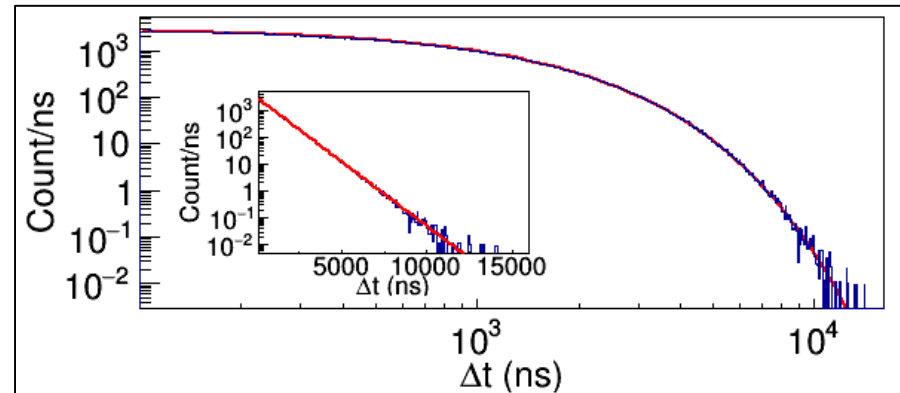
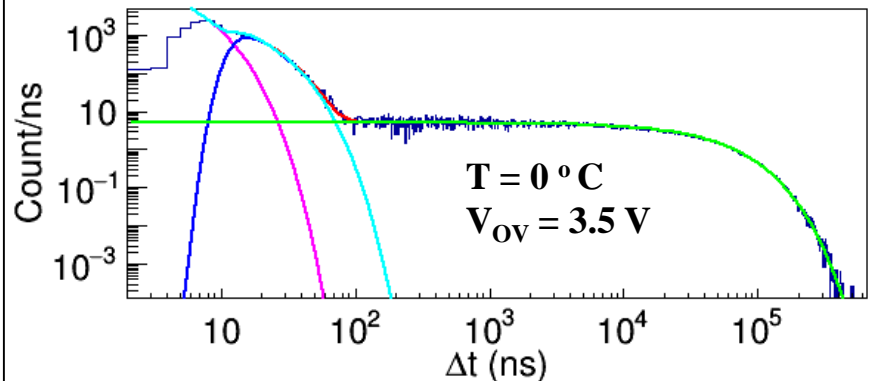
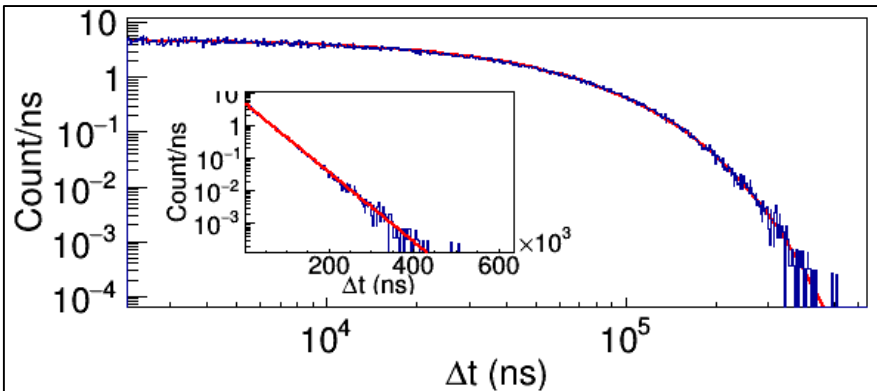
DeCT + AfterPulse



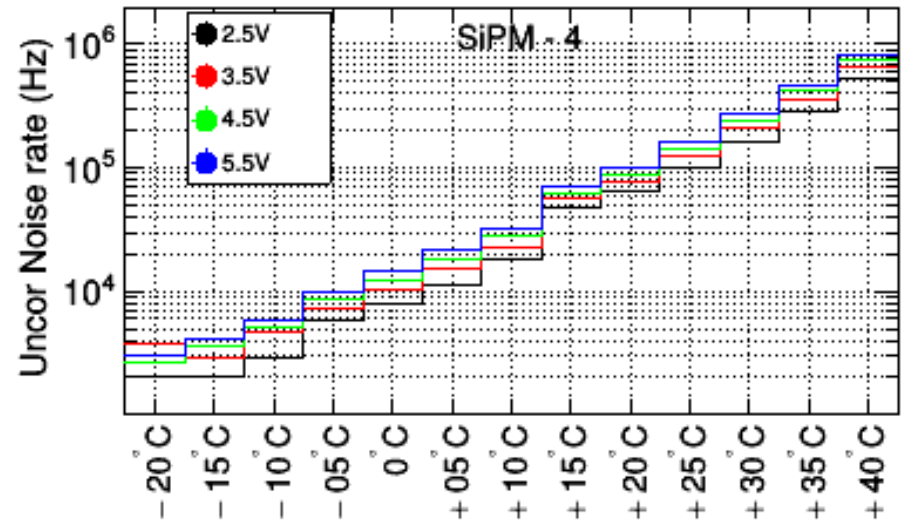
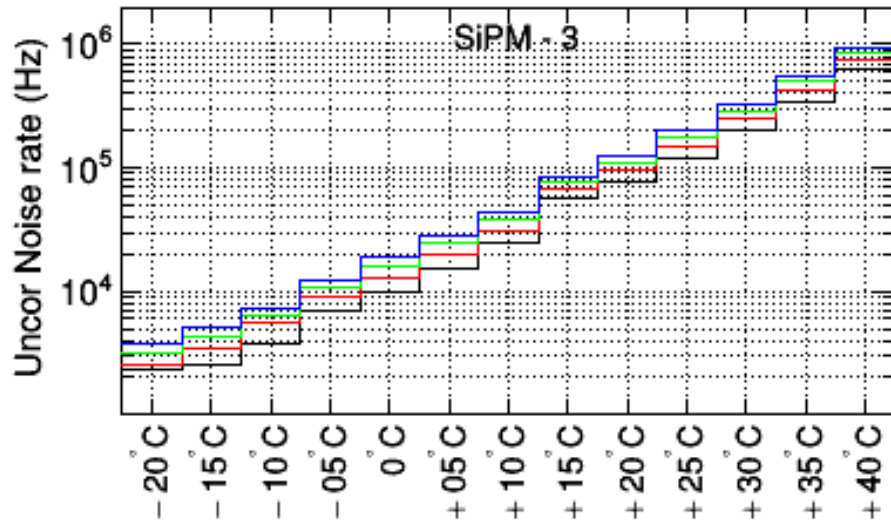
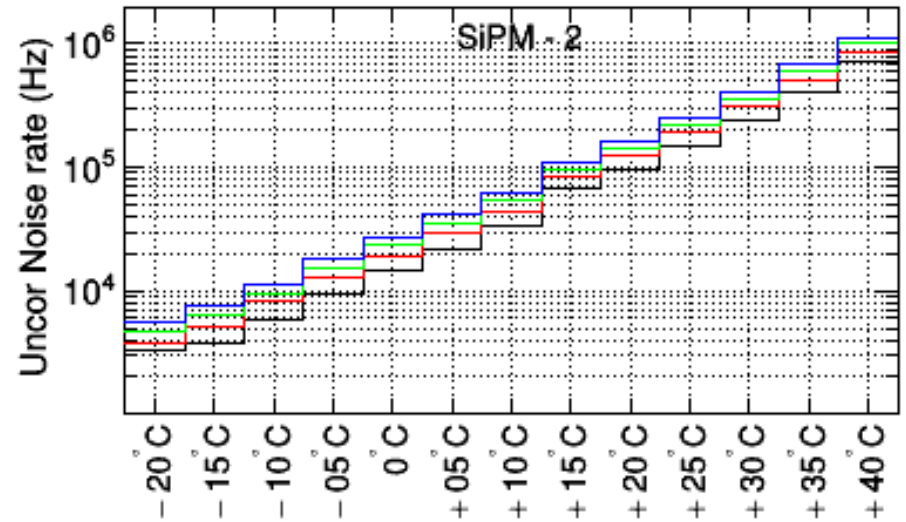
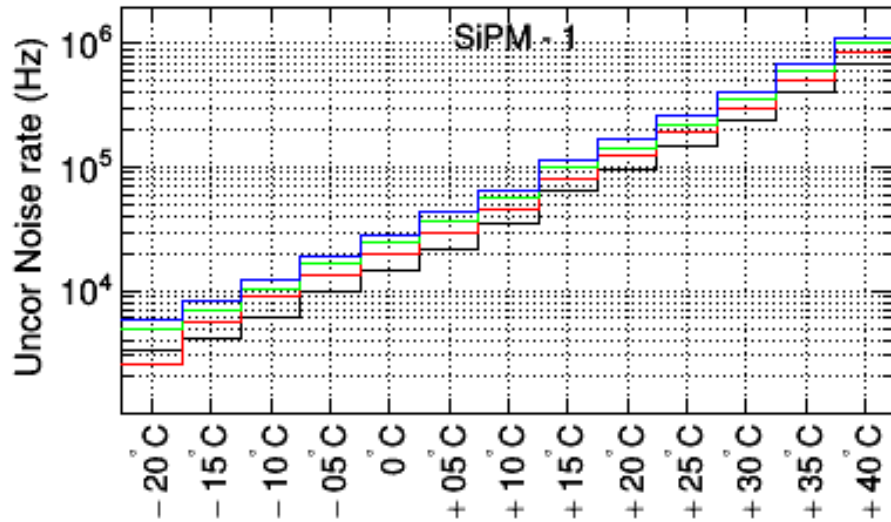
- Fit the tail part with simple exponential function to get the uncorrelated noise rate
- Combined fit :
 - Exponential for Delayed CT
 - Exponential with threshold due to pulse height selection criteria as well as resolution for AP
 - Fixed parameters of Uncorrelated noise
 - Exclude area of low statistics

Take projection on X-axis (Δt)

Difficult to separate out DeCT & AP

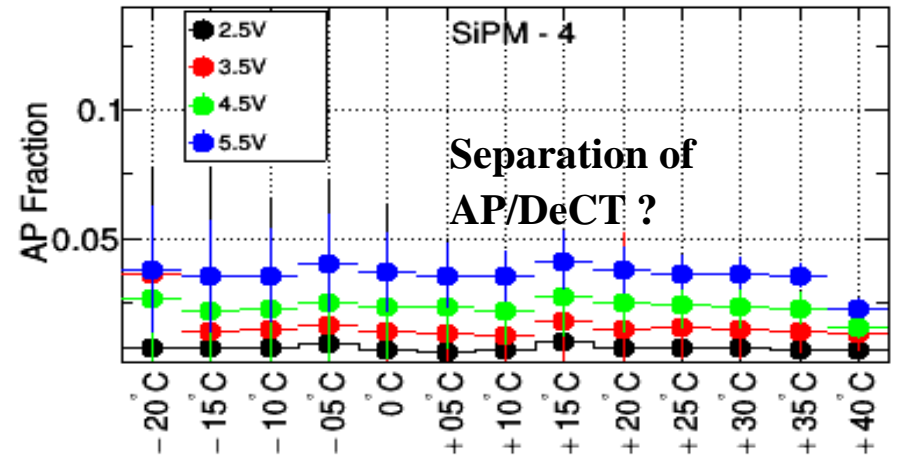
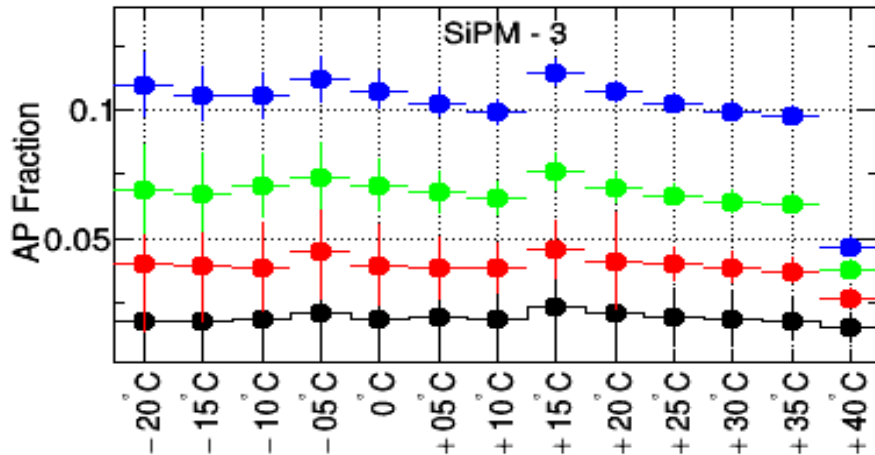
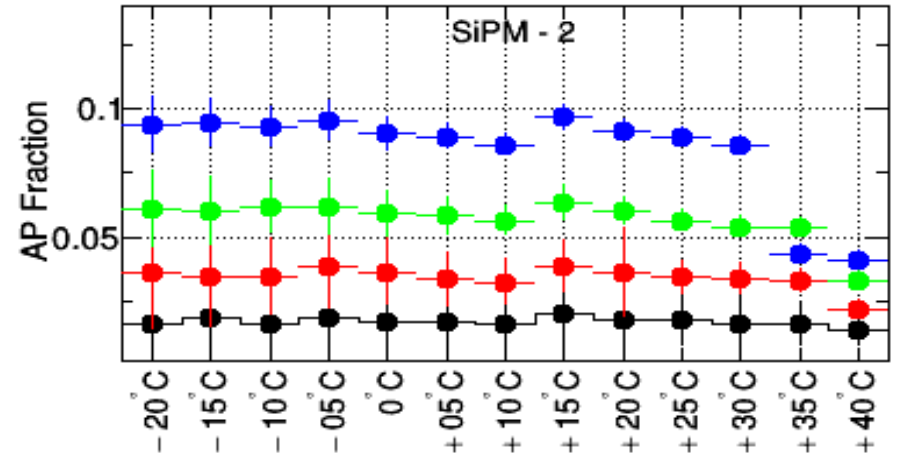
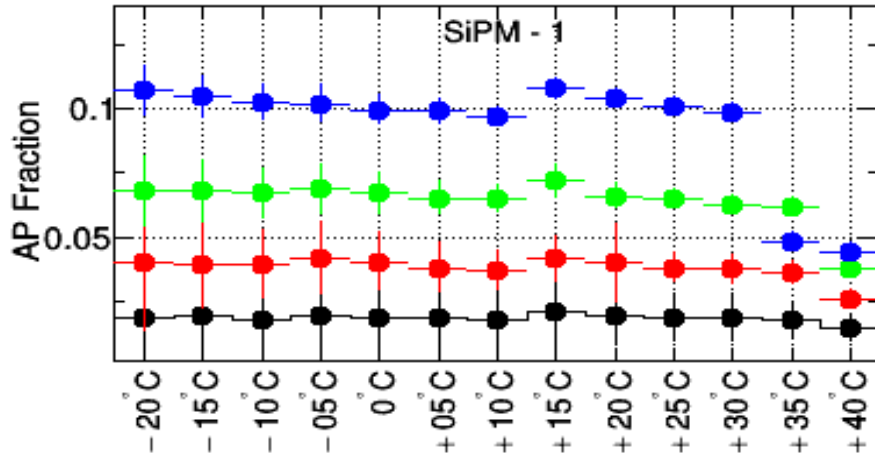


Uncorrelated noise rate : $V_{th} = 0.5p.e.$



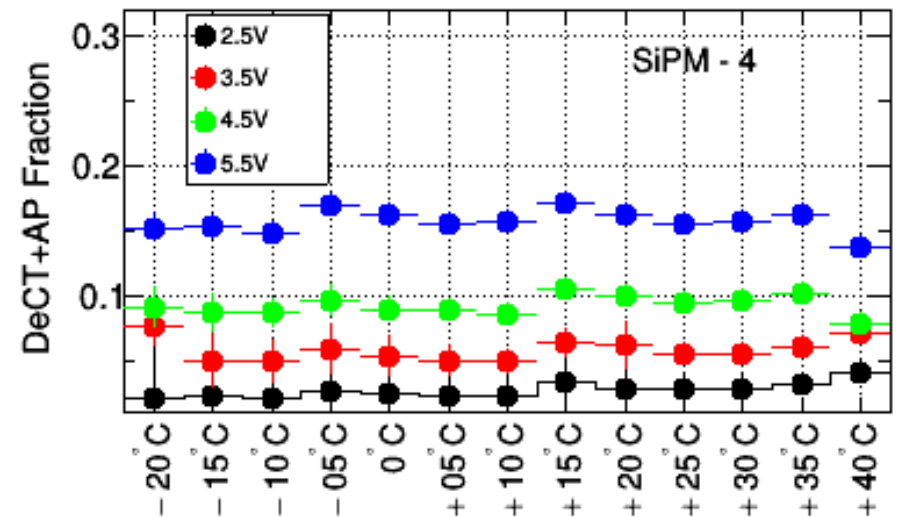
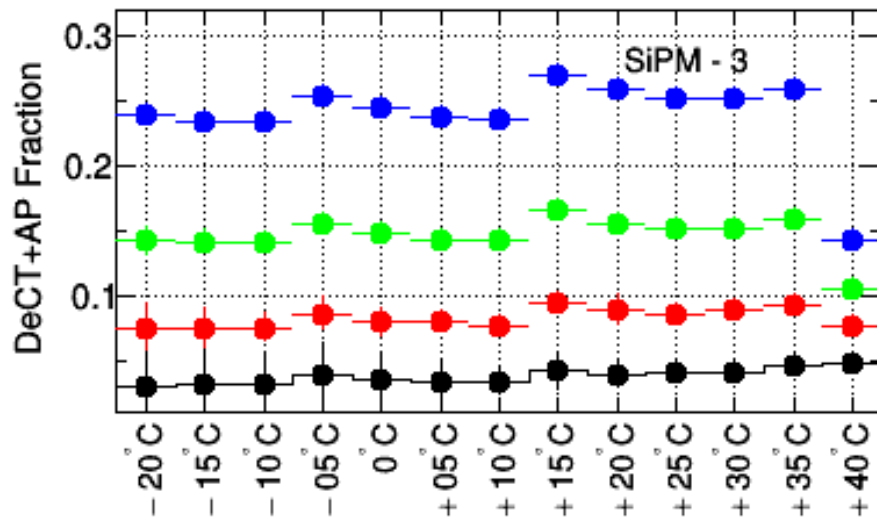
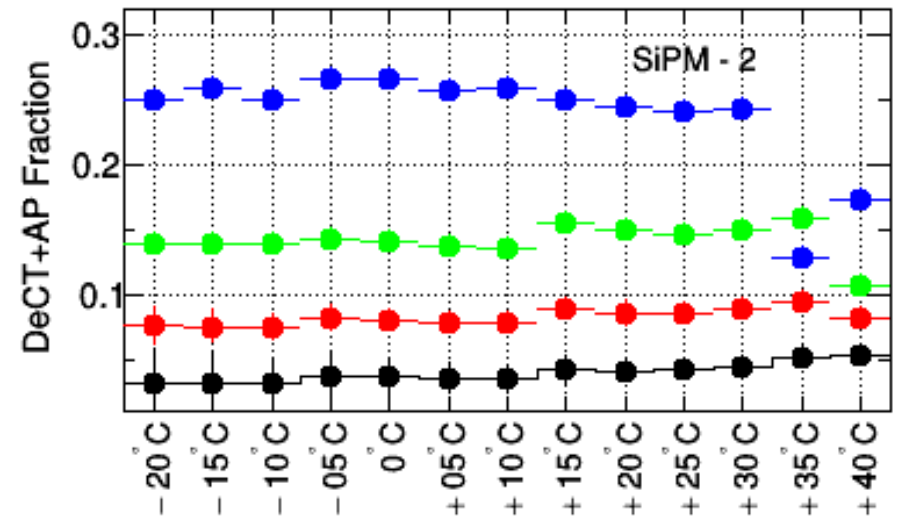
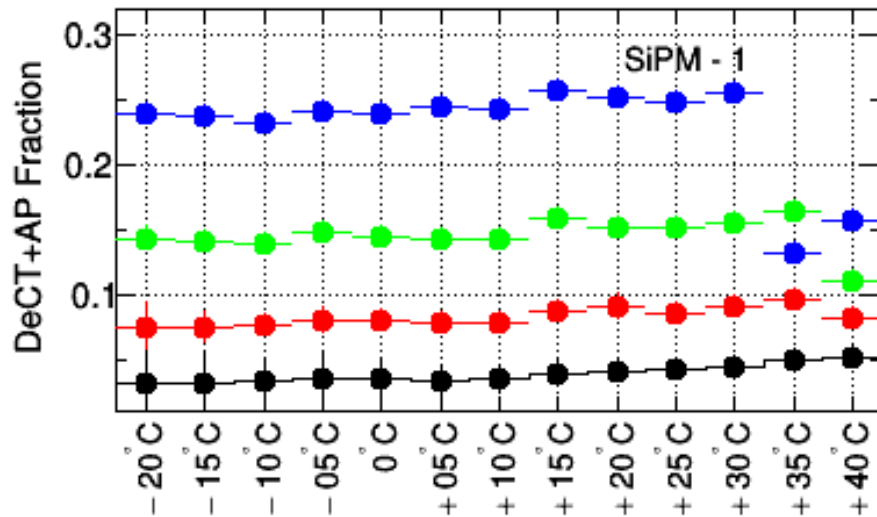
- As expected
 - Increase with Temperature as well as with V_{OV}

Fraction of After Pulse (from fit parameters)



- Change in Time scale at 15°C has a systematic shifts
- Behaviour of 4th SiPM is different than others !!
- Readings of High Temp + high V_{OV} (need to look in details)
- No increase of fraction with temperature (opposite to PromptOCT)
 - Extraction of AP from DeCT may be a possible source, or this is the feature

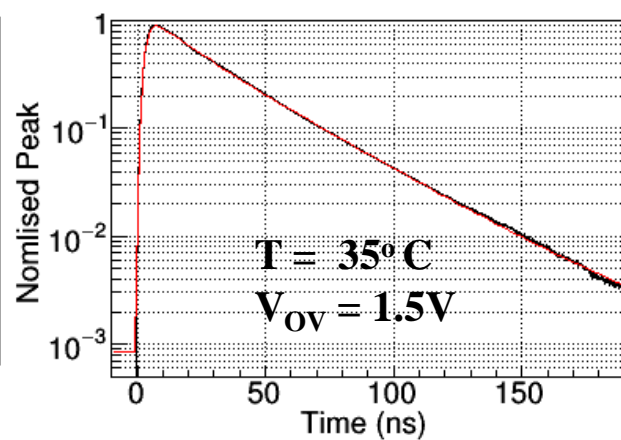
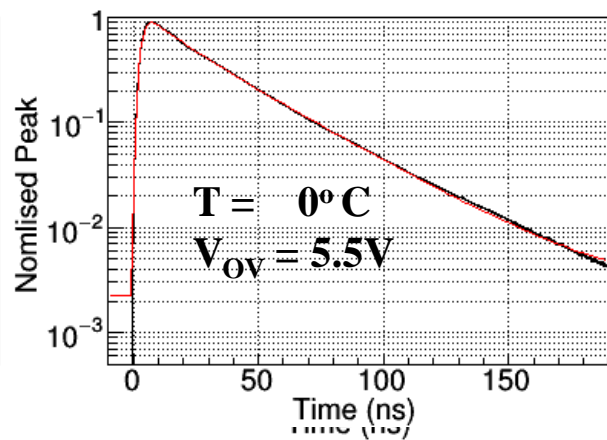
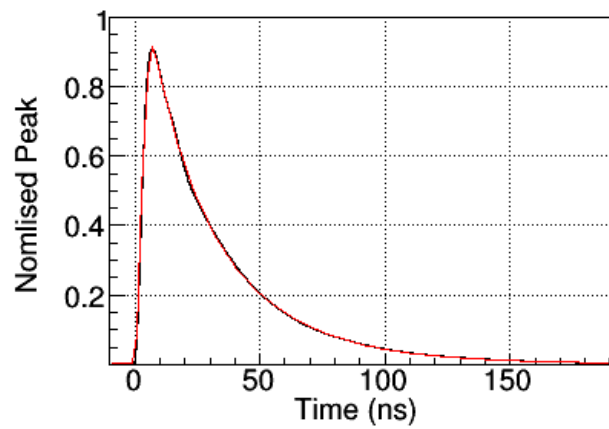
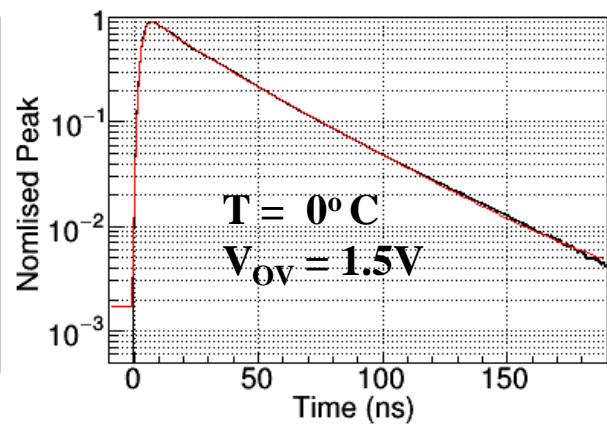
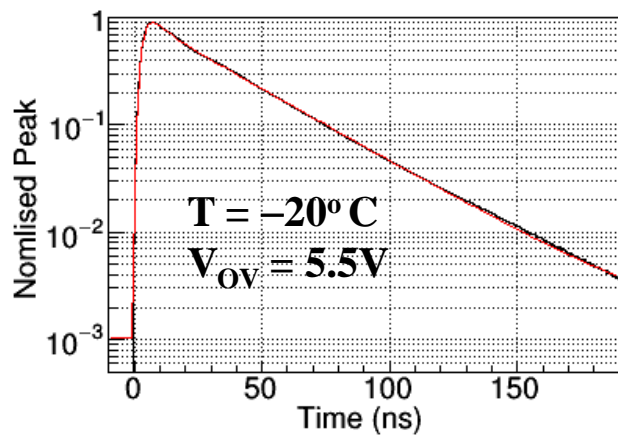
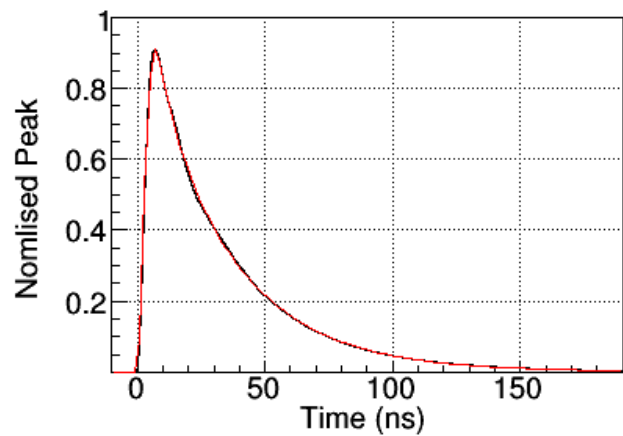
Fraction of DeCT+AP (Number count + Fit of Uncor noise)



- Problem with few V_{OV} at high Temperature (need to tune the algorithm)
- Nearly same trends of increase with temperature, what was observed in Prompt OCT

Conclusion

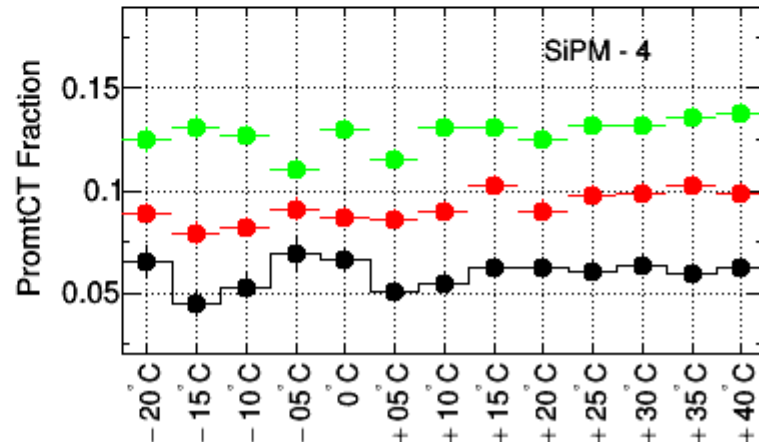
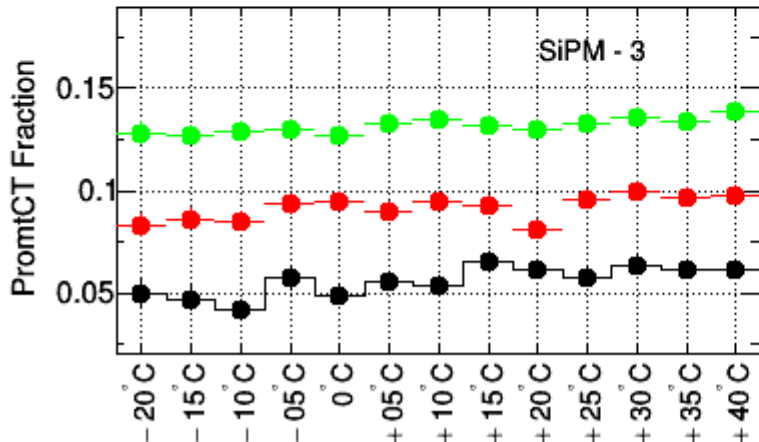
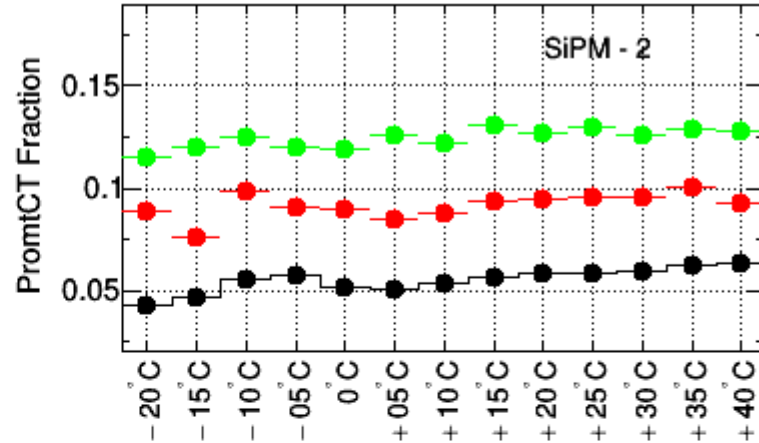
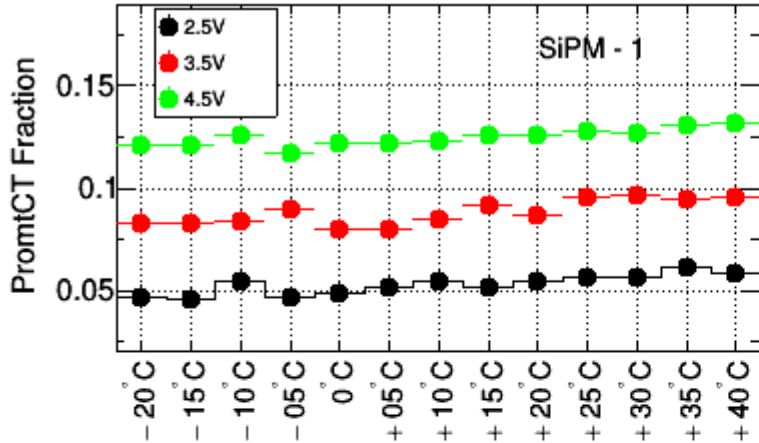
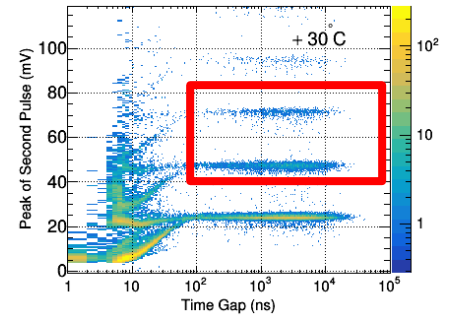
- **Variation of different noise properties have been studied as a function of temperature and V_{OV}**
- **Some qualitative features of those without any strong interpretations are**
 - **Both rise time and fall time of the spectrum varies with temperature as well as V_{OV} ,**
 - **Did not find any variation on recovery time due to limited statistics (but, does not look like the trends, what was observed for fall time),**
 - **Prompt cross talk increases with temperature and depends on the initial pulse,**
 - **AP does not vary with Temp and**
 - **Combination of DeCT+AP follows the same trends of PromptOCT**
- **Need more data to confirm all these properties**
- **Need to improve the readout to distinguish DeCT and AP as well as algorithms**



Prompt cross-talk

(Ratio of 3rd and 2nd band)

- Expect to have large ratio wrt 2nd/1st band

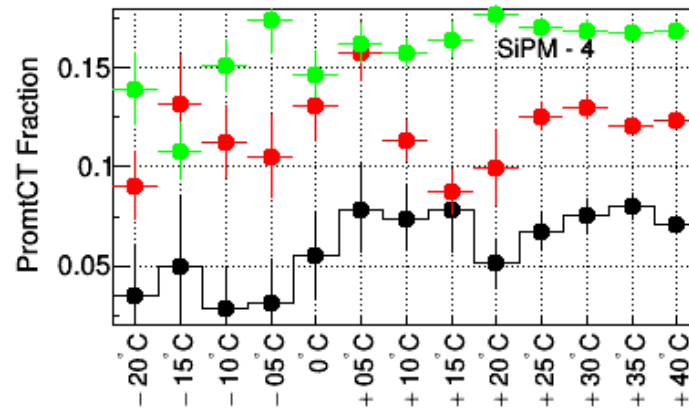
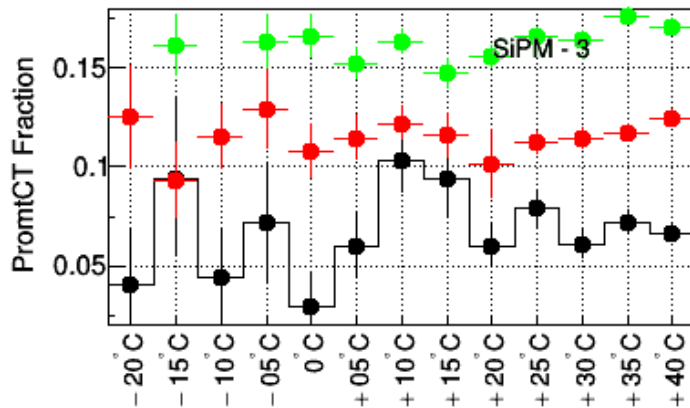
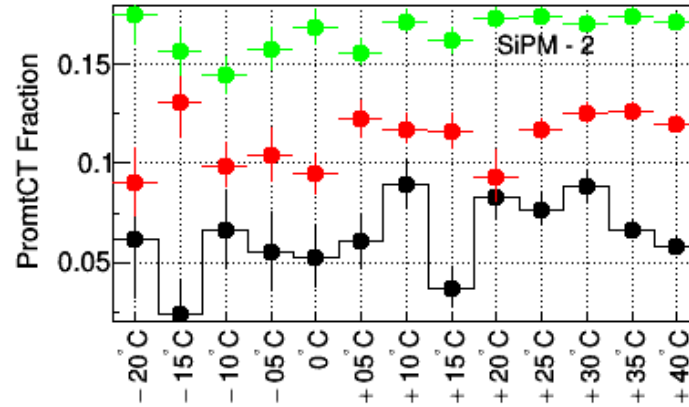
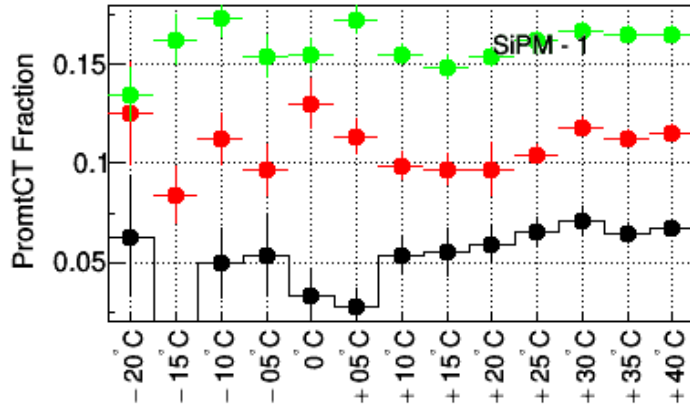
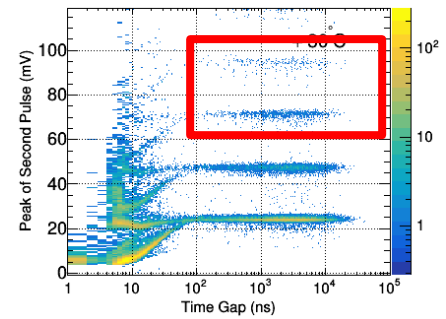


- Also a small variation with temperature,

Prompt cross-talk

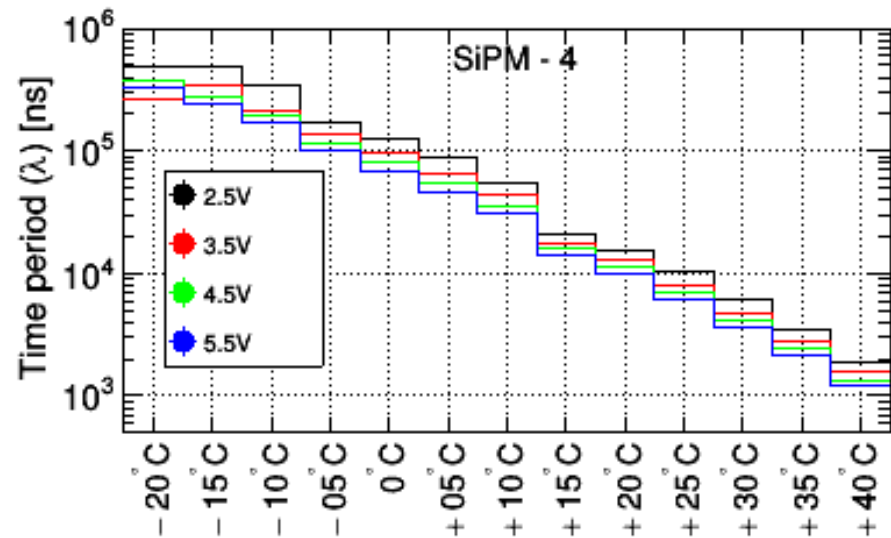
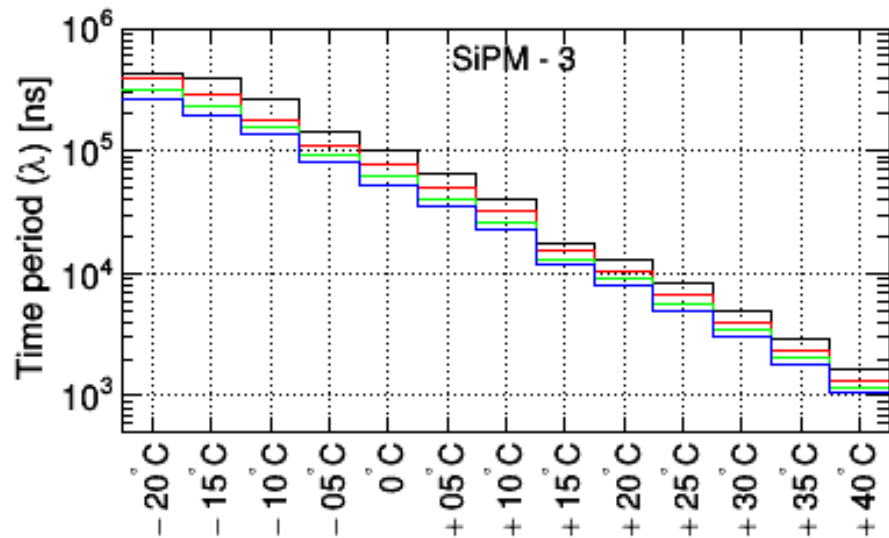
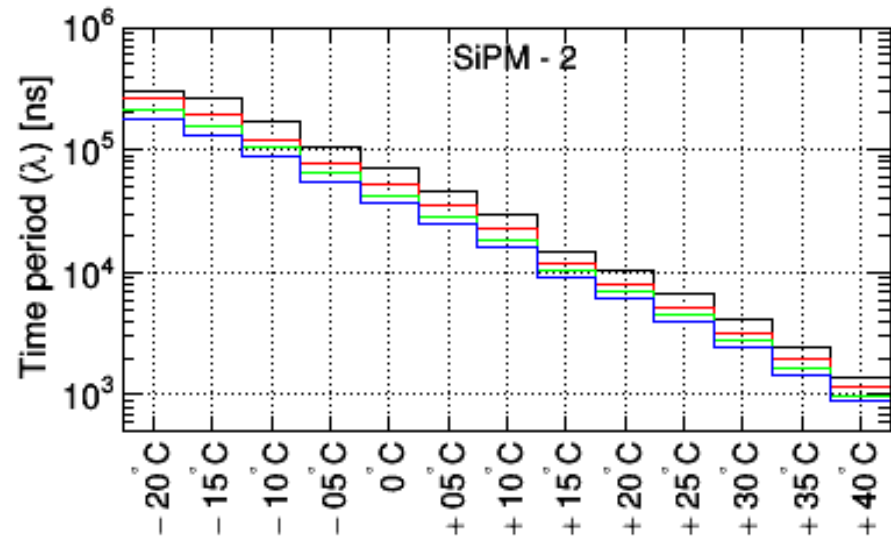
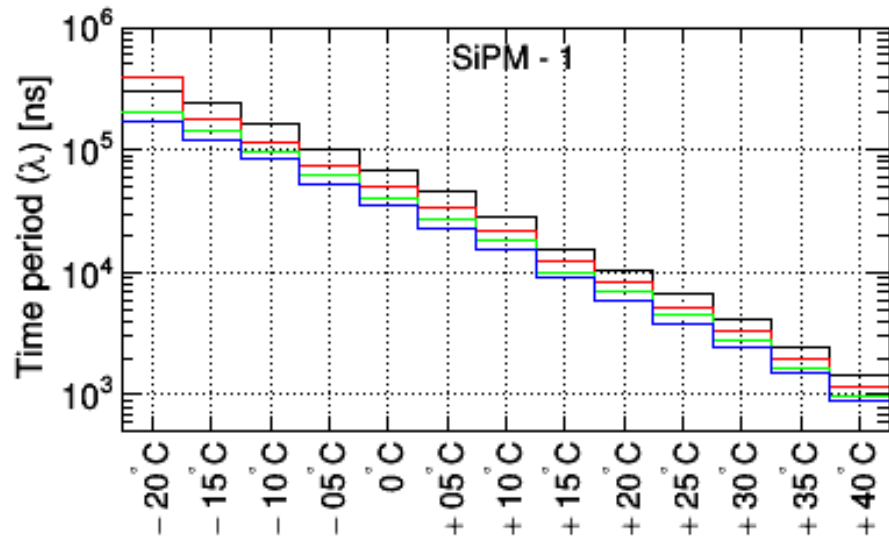
(Ratio of 4th and 3rd band)

- Expect to have larger ratio wrt to earlier

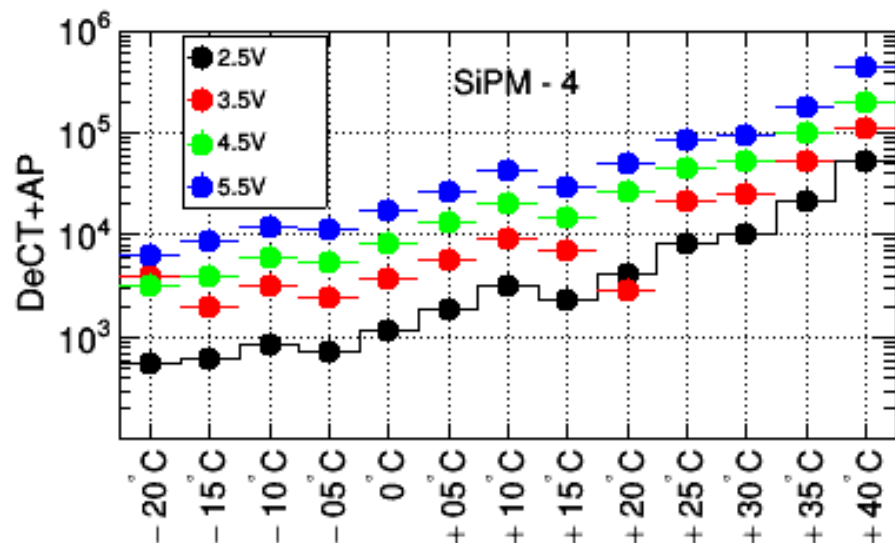
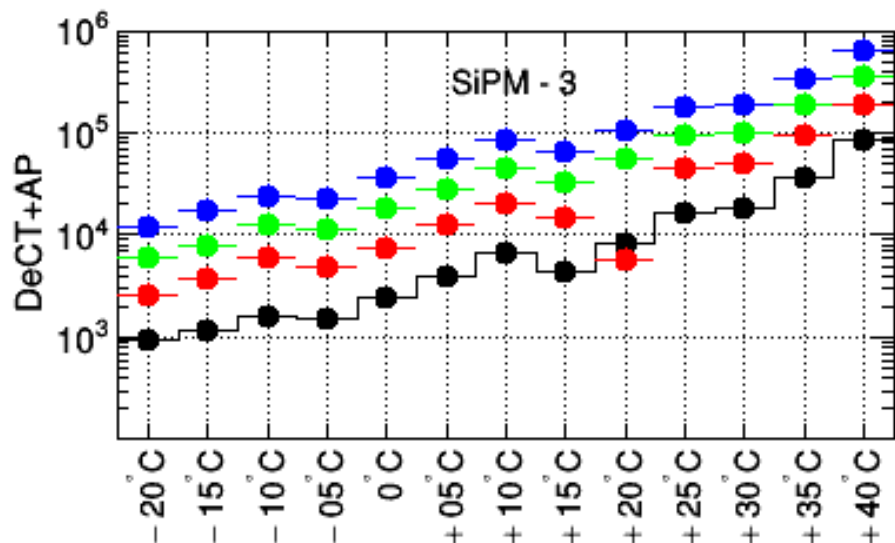
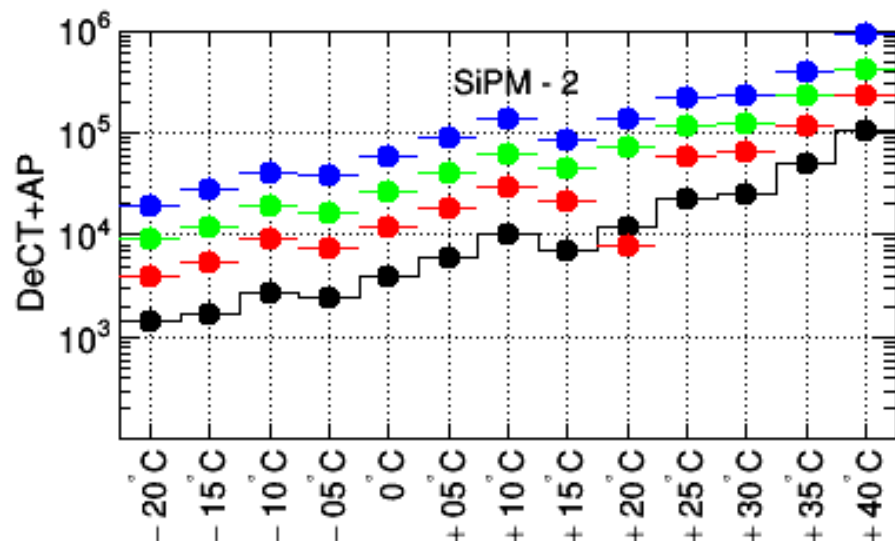
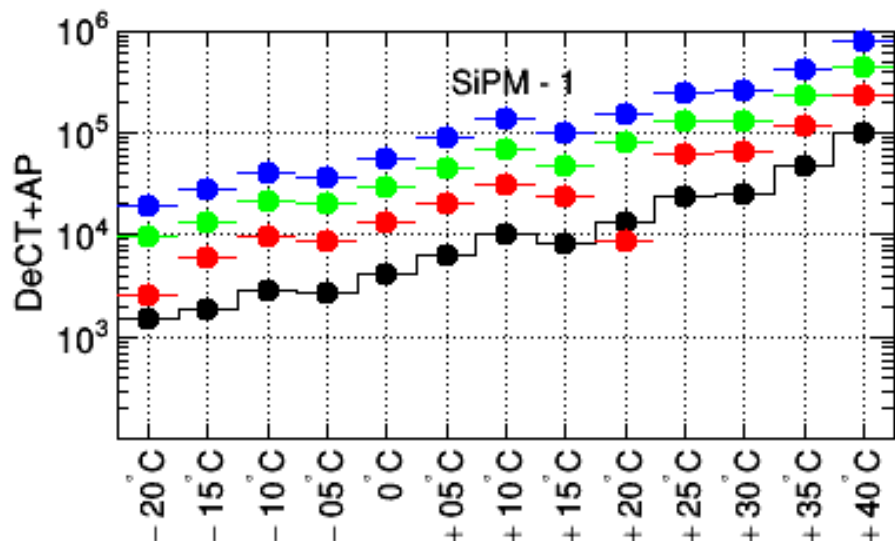


- Overall ratios are larger, but due to low larger statistical uncertainty, can not make any judgement on its trends or proportionality wrt to earlier two

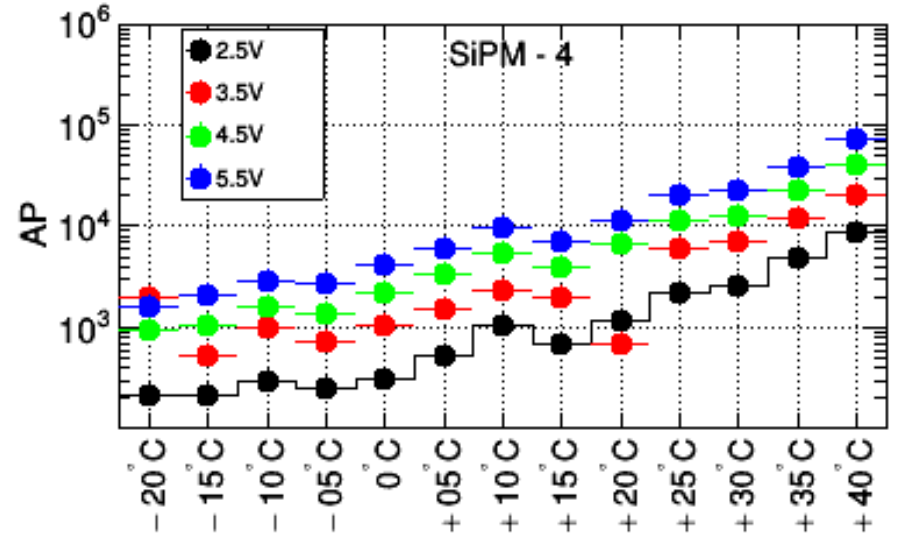
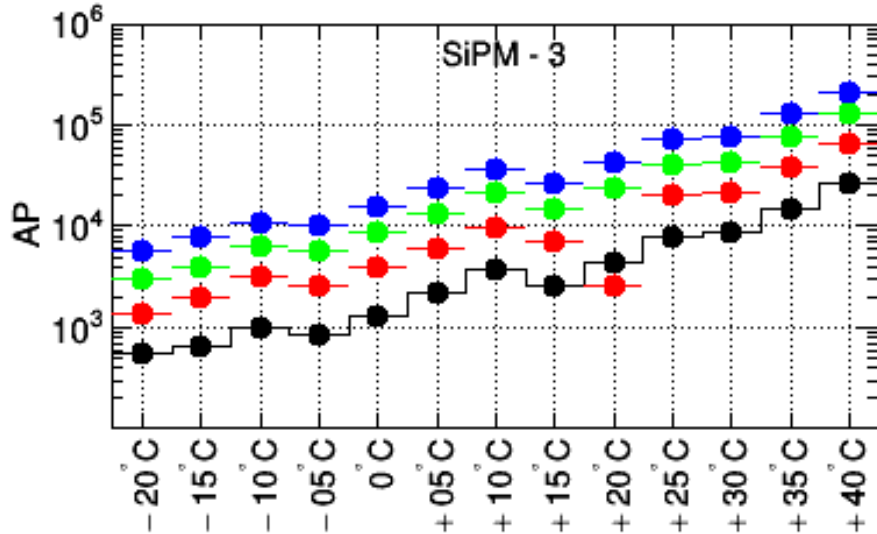
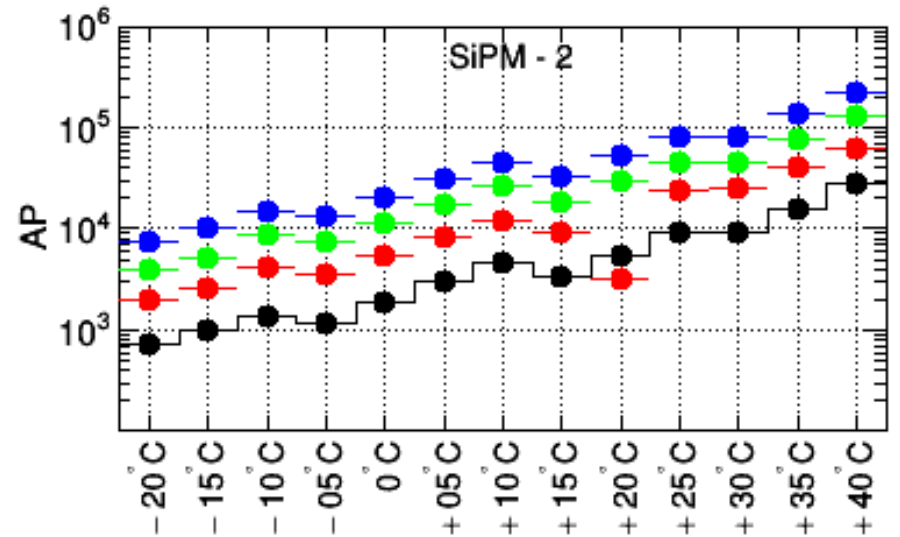
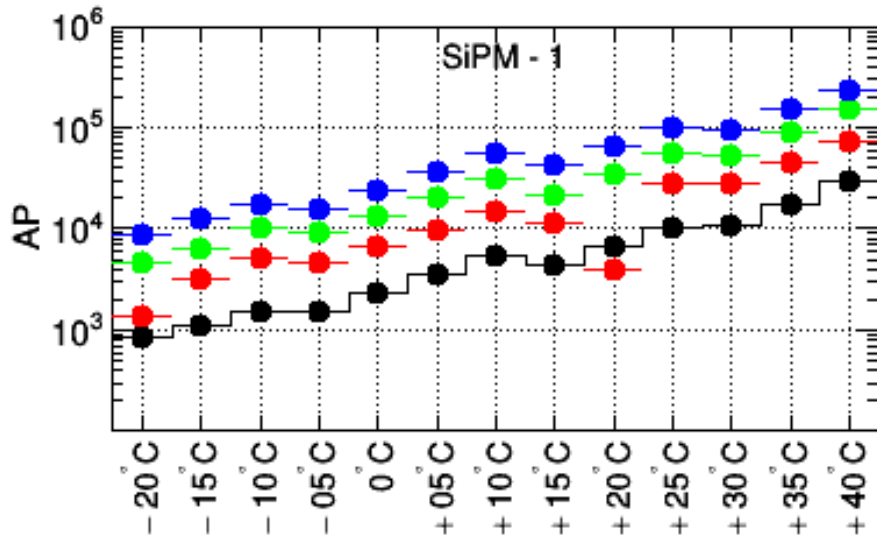
Time period for Uncorrelated noise



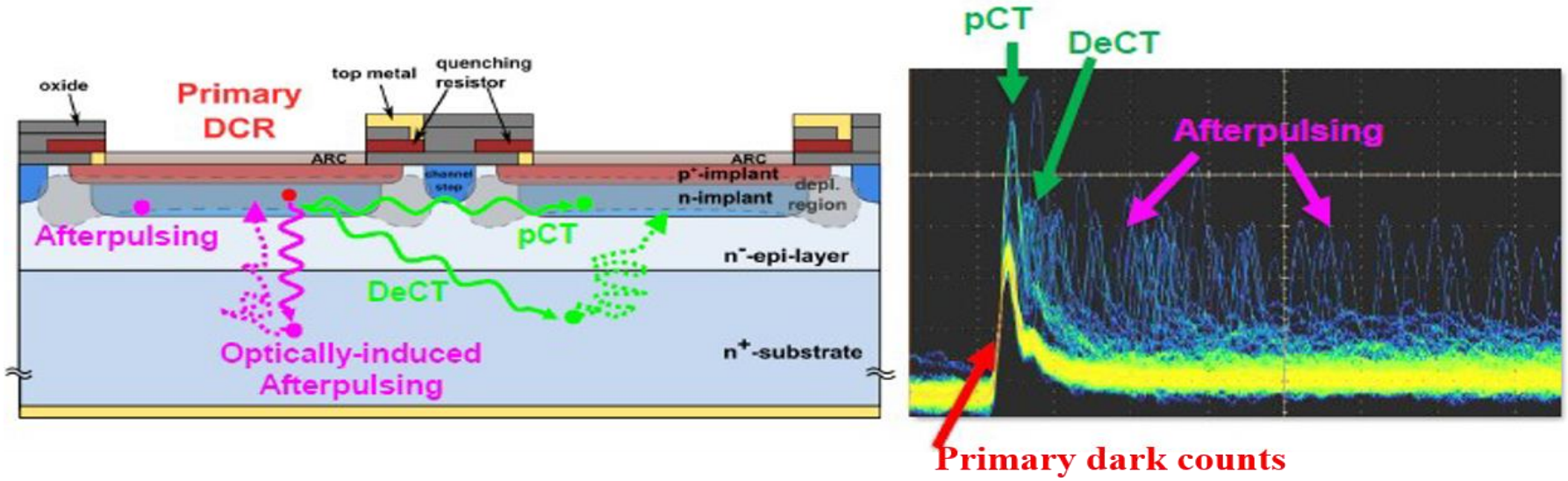
DeCT+AP (Arbitrary scale)



After pulse rate (arbitrary unit)



Explanation of different noise rate



- Own plots

